

Figure 1: TX & RX bus-level architectures, and clock receiver/rotation details.

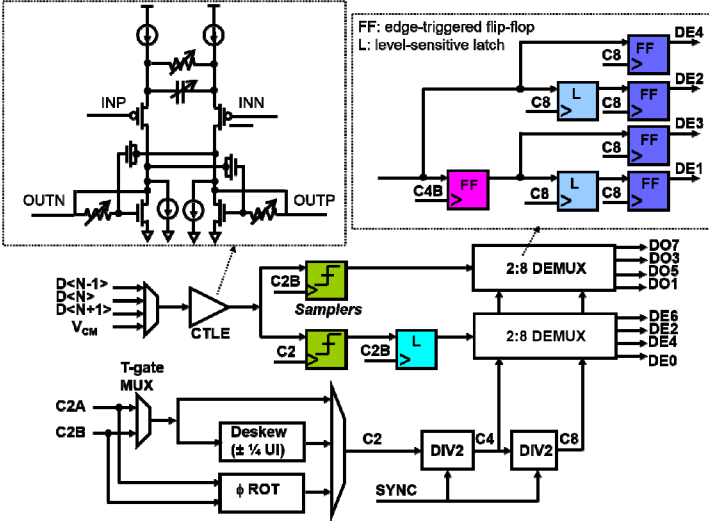


Figure 2: RX data path architecture.

and C2B are distributed to the RX lanes using the same low-skew distribution network as in the TX. In the proposed recalibration scheme, data from the two neighboring RX lanes that receive the same data input must be synchronized. The dual global phase rotators are time-aligned at start-up, and dividers within the RX lanes are synchronized as detailed below by sending a SYNC pulse across the bus using the same low-skew transmission line distribution techniques employed in the clock distribution.

### B. Receiver Data Path

To enable the proposed recalibration scheme, a 4-input MUX at the lane input selects data from one of three adjacent channels as described in the receiver data lane diagram in Fig. 2. A common-mode voltage  $V_{CM}$  is applied to the fourth input of the MUX such that a differential zero can be applied to the data path for offset calibration. The data path employs a CTLE with active inductor and shunt degeneration, which achieves 9dB of peaking at 8GHz. The active inductor forms a current mirror with the input NFETs used in the half-rate samplers. This processing of signals in the current domain mitigates the loss of DC voltage gain inherent to the active inductor topology. The DC gain of the data path is also enhanced by placing current sources in parallel with the active inductor load, which increases the transconductance of the CTLE input stage relative to the load impedance. After sampling, data is deserialized by a 2:8 DEMUX. Low latency is achieved in the DEMUX by directly sampling the latest data bit. As in our previous work [2], three lane deskew modes are implemented to support a range of links from low-skew MCM applications to higher skew PCB links. The SYNC pulse mentioned earlier flushes the CMOS dividers with known bit values such that all dividers are started in the same state. During a handoff between the two clocks at the beginning of a lane calibration, glitchless switching is

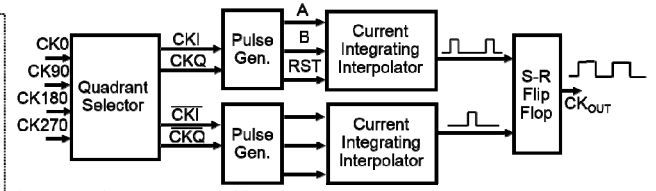


Figure 3: Phase rotator architecture.

achieved by first aligning the phase from the adjustable (calibration) phase rotator to match that of the rotator producing the data sampling clock. Once the clock phases are aligned, a transmission gate MUX passes both clocks into the receiver macro for a short time before finally switching completely to the calibration clock. A similar technique is employed after the lane has been recalibrated to restore the sampling clock. This procedure preserves the phase integrity of the clock signal into the divider such that divider synchronization is maintained across the bus.

### C. Phase Rotator

The RX phase rotator is based on the current-integrating interpolator cores described in [2, 4] and incorporates design enhancements to improve both power efficiency and linearity. The phase rotator operates on quadrature input clocks, as seen from the high-level block diagram in Figure 3. After quadrant selection, clocks CKI and CKQ are sent to a pulse generation circuit, which derives early and late signals A and B along with a reset signal RST. These signals are applied to the current-integrating phase interpolator core depicted in Figure 4. The early and late signals trigger the integration of currents from a current-steering DAC, along with small quiescent currents  $I_0$ , through a steering network as will be described shortly. As with our previous work [2], the early pulse edge triggers the integration of a variable current  $I_1$  from the DAC, while the late pulse triggers integration of the remainder of the DAC current  $I_1 + I_2$ . This action results in an integrator output waveform that crosses a threshold level  $V_{TH}$  with a programmable amount of delay, as seen in the timing diagram of Figure 5. In contrast to our prior work that relied on an inverter threshold, this work improves robustness by using a differential comparator to detect the threshold crossing and ultimately trigger the S-R flip-flop of Figure 3. A replica integrator is also employed that only operates on the quiescent currents, such that their contribution to the differential signal (Fig. 5) is cancelled. Signals developed across the integration and replica load capacitors  $C_{INT}$  are level-shifted via switched series capacitors  $C_S$  [5] to ensure proper common-mode levels at the comparator input. The use of a differential comparator and replica integrator also reduces the sensitivity of the circuit to power supply noise. In order to maximize the integrator reset time after the triggering of the comparator, the clock output signal CKO is also used to self-reset the integrators via pull-up devices M1 and M2. A second reset signal

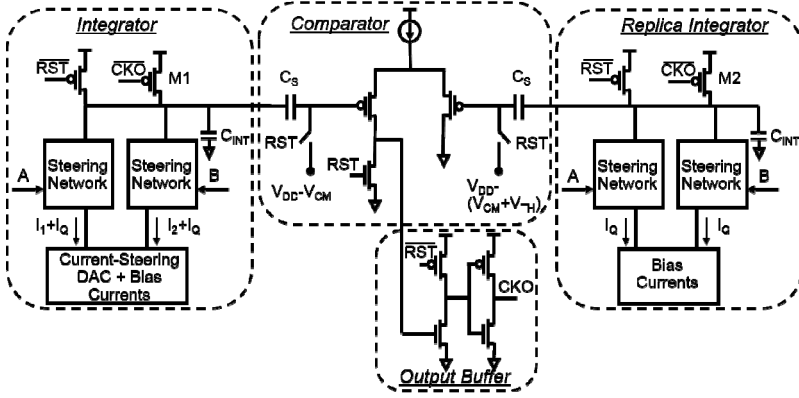


Figure 4: Current-integrating phase interpolator.

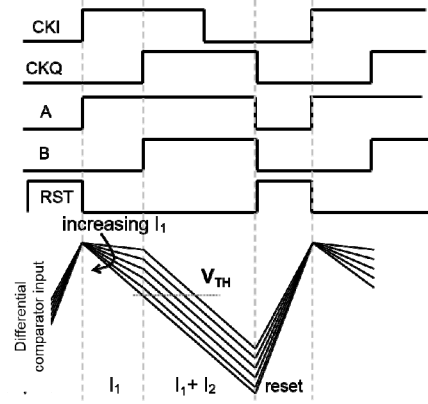


Figure 5: Simplified timing diagram of the current-integrating phase interpolator.

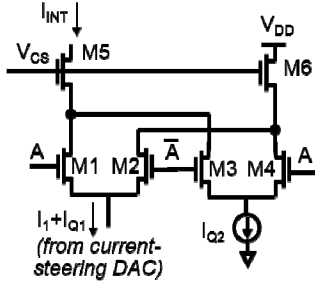


Figure 6: Details of the steering network within the phase interpolator.

RST is derived by the pulse generator from the falling edge of CKQ to enhance the integrator resetting. Note that for clarity, Figure 5 only depicts this resetting action, and not the self-resetting action due to feedback from CKO.

Details of the steering network within the interpolator core are illustrated in Figure 6. The figure shows the operation of a steering network triggered by early signal A, although identical steering networks are employed in the path triggered by late signal B, as well as in the replica integrator. Once triggered by A, current from the DAC as well as a small quiescent current  $I_{Q1}$  is steered to the integration node. The inclusion of  $I_{Q1}$  avoids non-idealities

associated with the integration of near-zero currents at codes near the extremes of the interpolator range [2]. A cascode device M5 isolates the integration node from parasitic capacitances in the rest of the steering network. Once signal A goes low, current from the DAC is steered to a dummy load M6. During this reset period, a second quiescent current  $I_{Q2}$  is steered to the integration node. Maintaining this current through the cascode transistor M5 avoids slow transients associated with the charging and discharging of its source node during each integration cycle.

#### D. Transmitter Data Path

Figure 7 shows details of the 16-Gb/s data transmitter which includes an 8:1 serializer, output driver, and local clocking circuitry. Duty-cycle correction is applied to the input half-rate clock before dividing to produce 8-phases of a C8 (2 GHz) clock. These clock phases are used to directly serialize the 2-Gb/s input data using a transmission-gate serializer. Each transmission gate is enabled for 1-UI by ANDing two phases of the C8 clocks. While transmission gate structures have been used for 4:1 serializers [2, 6], the use of eighth-rate clocks in this work enables a very low-latency 8:1 serializer. Serialized data is transmitted by a PFET CML driver with adjustable launch amplitude of between 100mVppd and 400mVppd [2].

### III. EXPERIMENTAL RESULTS

A C4-limited test chip occupying  $2.5 \times 3.7 \text{ mm}^2$  was fabricated in 32nm SOI CMOS technology. Test chips in organic SLCs were mounted to Megtron-6 test boards with matched channel lengths varying from 0.75" to 10". A board with 10" channels is shown in Figure 8. Figure 9 shows aggregate bathtub curves for all 16 lanes in the parallel interface when running 16Gb/s PRBS31 data over the 0.75" and 10" traces. Bus-level timing margin of 30% at a BER of  $1\text{E-}9$  is achieved launching 100mVppd data across the 0.75" links, and is limited by underdamped ref-

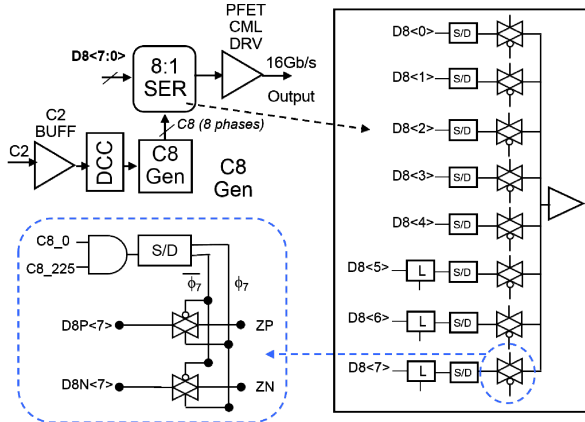


Figure 7: TX data path, including 8:1 serializer with 8-phase  $1/8^{\text{th}}$  rate (2GHz) clocks.

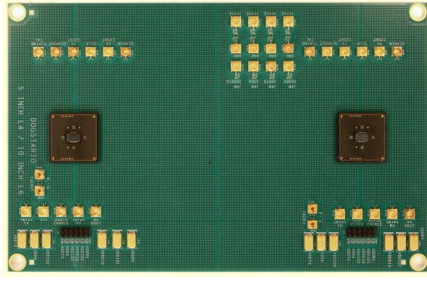


Figure 8: Megtron-6 test board with two packaged test chips interconnected via 10'' traces.

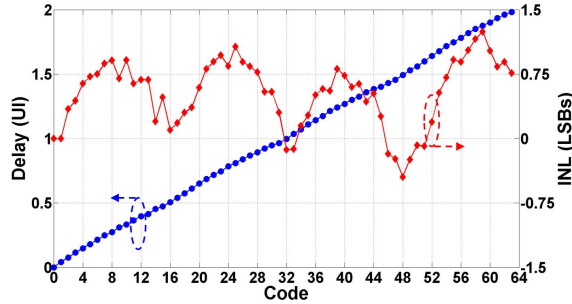


Figure 10: Phase rotator transfer characteristic and integral nonlinearity.

lections. The measured link efficiency is 1.81pJ/bit, including 0.55pJ/bit from the 1V TX, 1.18pJ/bit from the 1V RX, and 0.08pJ/bit from the amortized 1V PLL. Data chronization between two RX lanes was experimentally verified, and glitchless handoff between the two clocks C2A and C2B entering an RX lane was demonstrated without introducing bit errors or losing divider synchronization between lanes. Across 10'' links with 10dB C4-to-C4 loss, 200mVppd data is recovered with a bus-level timing margin of 40% at an efficiency of 1.93pJ/bit. The measured phase rotator transfer characteristic is depicted in Figure 10. The measured INL is better than 1.2LSBs, making this phase rotator suitable for a digital-CDR-based Rx in addition to the source-synchronous links targeted in this work.

#### IV. CONCLUSIONS

A 16-lane, 16-Gb/s per lane source-synchronous I/O is reported in 32nm SOI CMOS technology. The architecture employs a receiver redundancy scheme that enables periodic Rx lane recalibration while supporting continuous data transmission, without excessive power or area penalty. Several innovative circuit and architecture features have been described, including an active-inductor CTLE that directly interfaces to the sampling latch, low-latency serializer and deserializer, and a phase rotator based on current-integrating phase interpolators with improved linearity and supply rejection as compared to prior art [2]. Table 1 compares this work with recent I/Os operating

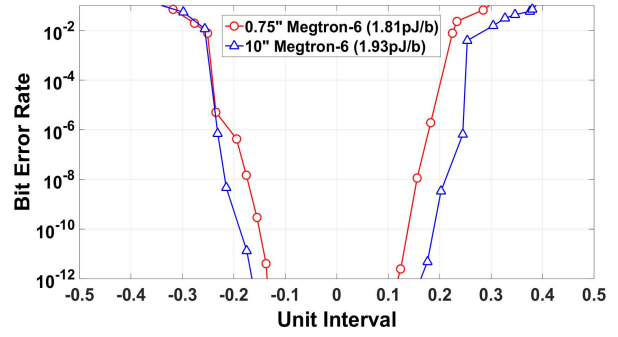


Figure 9: Aggregate bathtub curves for 16 lanes sending 16Gb/s PRBS31 data

	[7]	[8]	[9]	[10]	This Work	
Technology	65nm	40nm	40nm	32nm	32nm SOI	
Per-Lane Data Rate (Gb/s)	16	16	16/20	16	16	
Equalization	TX FFE-5, RX CTLE (CTRL)	Coded differential signaling	TX FFE-2 RX CTLE RX DFE-1	TX FFE-3 RX CTLE	RX CTLE	
Channel Loss (dB)	15	10	15	11	6.2	10
Power Efficiency (pJ/bit)	13 (CTRL)/ 8 (DRAM)	4.1	5.3/6.1	2.6	1.8	1.9

Table 1: Comparison with recently reported 16-Gb/s I/Os.

near 16Gb/s [7-10]. This work achieves better than 2pJ/b power efficiency while equalizing 10dB of channel loss, making this suitable for source-synchronous power critical applications with short-to-moderate reach.

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